## Notice of References Cited Application/Control No. 10/533,644 Examiner Mark Blouin Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0117928 A1	06-2003	Choi et al.	369/75.2
*	В	US-2003/0086358 A1	05-2003	Park et al.	369/248
*	С	US-2003/0016616 A1	01-2003	Nishimura et al.	369/223
*	D	US-6,341,115 B1	01-2002	Otani et al.	720/653
	E	US-			
	F	US-			
	G	US-			
	Τ	US-			
	1	US-			
	7	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0			A		
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	V	
	x	

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.